

Dictionary Resilient to Memory Faults

Soft memory errors

Nowadays memories

- High frequencies, small geometries, complex circuitry, low voltages
- These improvements come at the cost of **reliability**

Soft memory errors

- Random bit flips, corrupting the content of the affected memory cells
- Multiple causes, e.g. power failures, alpha particles, cosmic rays

Occurrence rates

- Every few months for an usual RAM
- Becomes a serious concern when many memories are involved, e.g. large clusters
- Trends point that soft memory error rates are expected to grow

Malicious usages

Break two JVM implementations

- Increase the occurrence rate of soft memory errors by heating the RAM

Cryptography

- Cryptographic protocols provably secure become insecure

Break smart-cards

Algorithms in unreliable memory

Most algorithms assume reliable storage

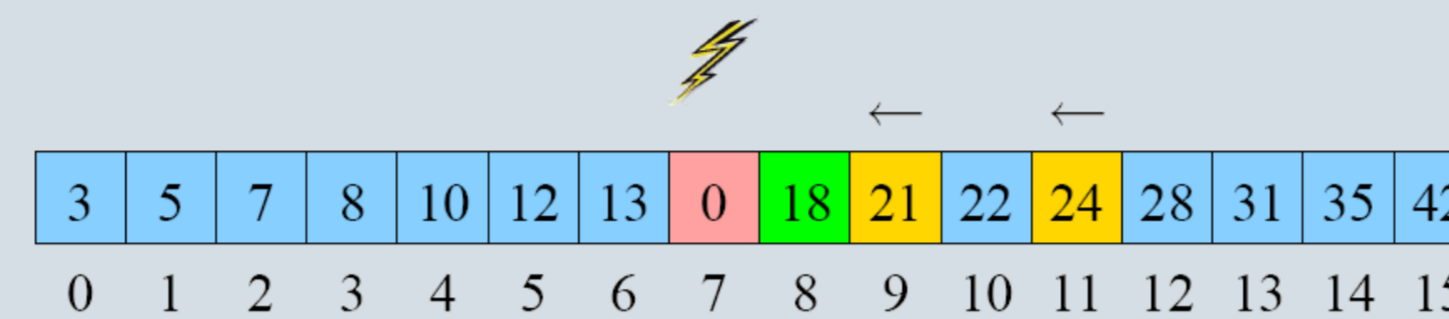


Figure 1. *Classical binary search in corrupted memory.*
The search key $e=3$.

Algorithms which are unaware of memory corruptions may be seriously affected

Classical binary search in a sorted array in Figure 1:

- Output is incorrect (algorithm outputs NO)
- Search path ends very far from the correct position
- A single corruption suffices

Faulty-memory RAM

- A Random Access Machine (RAM) with possibly corrupted cells
- Corruptions occur at any time and at any place
- Corrupted and uncorrupted cells cannot be distinguished
- No increase in space complexity
- At most δ corruptions possible, $O(1)$ corruption-free cells
- Resilient algorithms:** work correctly on uncorrupted cells

Resilient dictionaries

Searching operation returns

- YES**, if there exists an uncorrupted value equal to the search key
- NO**, if there are no elements, corrupted or uncorrupted, matching the search key
- YES/NO**, if a corrupted element matches the search key.

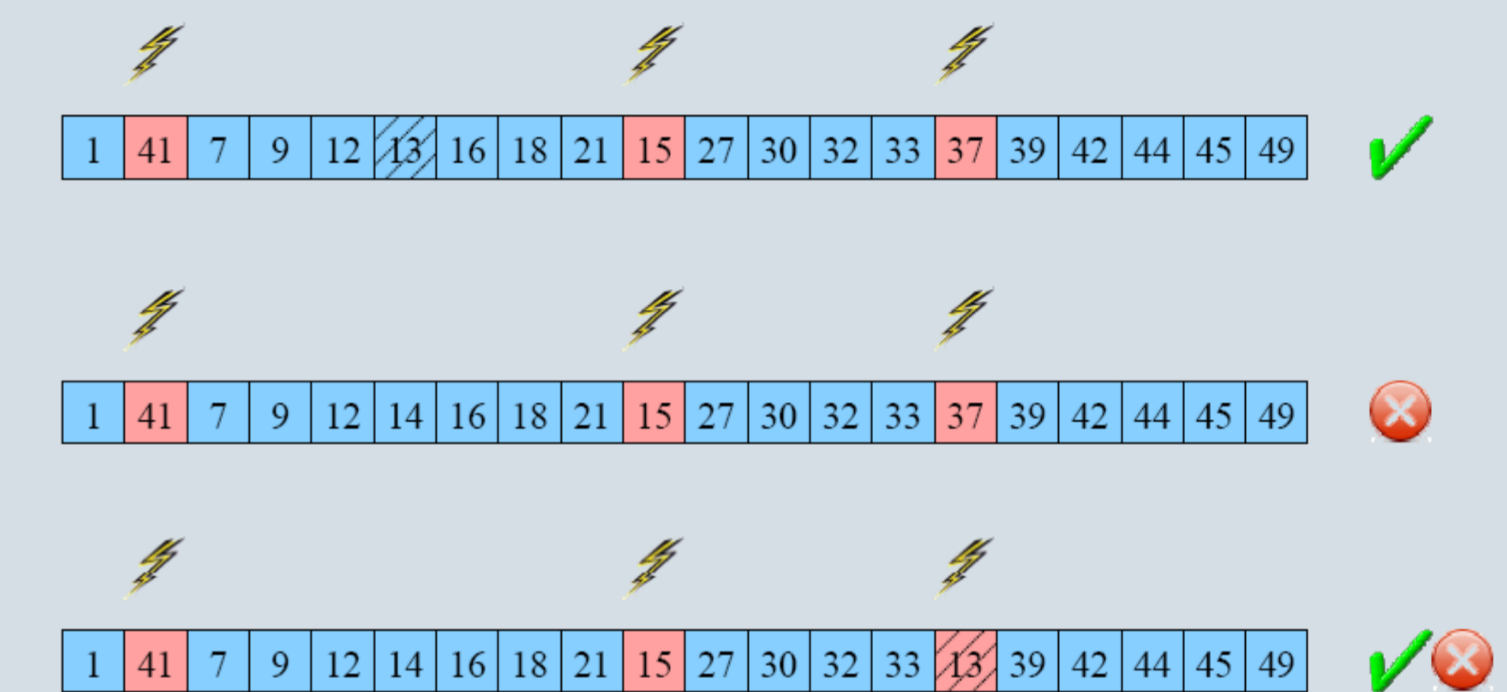


Figure 2. *Outputs of resilient dictionaries for search key $e=13$.*

Resilient dictionaries

- Static: $\theta(\log n + \delta)$ worst case time [1-3]
- Dynamic: $\theta(\log n + \delta)$ worst case time for searches, $\theta(\log n + \delta)$ amortized time for updates [3]

References

- [1] I. Finocchi and G. F. Italiano. *Sorting and searching in faulty memories*. In ACM STOC'04, 101–110.
- [2] I. Finocchi, F. Grandoni, and G. F. Italiano. *Optimal sorting and searching in the presence of memory faults*. In ICALP'06, 286–298.
- [3] G.S. Brodal, R. Fagerberg, I. Finocchi, F. Grandoni, G.F. Italiano, A. Jørgensen, G. Moruz, and T. Mølhave. *Optimal resilient dictionaries*. In ESA'07, 347-358.